## M ACH120-12/15

High-Performance EE CMOS Programmable Logic

## DISTINCTIVE CHARACTERISTICS

- 68 Pins in PLCC
- 48 Macrocells
- 12 nst $_{\text {PD }}$ Commercial, 18 ns t $_{P D}$ Industrial
- 77 M Hz forct
- 48 I/Os; 4 dedicated inputs; 4 dedicated inputs/clocks
- 48 Outputs
- 48 Flip-flops; 4 clock choices
- 4 "PALCE26V12" blocks
- SpeedLocking ${ }^{\text {n }}$ for guaranteed fixed timing
- Pin-compatible with the MACH221


## GENERAL DESCRIPTION

The MACH120 is a member of the high-performance EE CMOS MACH ${ }^{\circledR} 1$ family. This device has approximately five times the logic macrocell capability of the popular PALCE22V10 without loss of speed.
The MACH120 consists of four PAL ${ }^{\circledR}$ blocks interconnected by a programmable switch matrix. The switch matrix connects the PAL blocks to each other and to all input pins, providing a high degree of connectivity between the fully-connected PAL blocks. This allows designs to be placed and routed efficiently.

The MACH120 macrocell provides either registered or combinatorial outputs with programmable polarity. If a registered configuration is chosen, the register can be configured as D-type or T-type to help reduce the number of product terms. The register type decision can be made by the designer or by the software. All macrocells can be connected to an I/O cell. If a buried macrocell is desired, the internal feedback path from the macrocell can be used, which frees up the I/O pin for use as an input.


## CONNECTION DIAGRAM

## Top View

PLCC


Block C
14129J-2

## Note:

Pin-compatible with the MACH220 and MACH221.

## PIN DESIGNATIONS

CLK/I = Clock or Input
GND = Ground
I = Input
I/O = Input/Output
VCC = Supply Voltage

## ORDERING INFORMATION

## Commercial Products

Vantis programmable logic products for commercial applications are available with several ordering options. The order number (Valid Combination) is formed by a combination of:


| Valid Combinations |  |
| :--- | :---: |
| MACH120-12 | JC |
| MACH120-15 |  |

## Valid Combinations

The Valid Combinations table lists configurations planned to be supported in volume for this device. Consult the local Vantis sales office to confirm availability of specific valid combinations and to check on newly released combinations.

## ORDERING INFORMATION

## Industrial Products

Vantis programmable logic products for industrial applications are available with several ordering options. The order number (Valid Combination) is formed by a combination of:


## Valid Combinations

The Valid Combinations table lists configurations planned to be supported in volume for this device. Consult the local Vantis sales office to confirm availability of specific valid combinations and to check on newly released combinations.

## FUNCTIONAL DESCRIPTION

The MACH120 consists of four PAL blocks connected by a switch matrix. There are 48 I/O pins and 4 dedicated input pins feeding the switch matrix. These signals are distributed to the four PAL blocks for efficient design implementation. There are 4 clock pins that can also be used as dedicated inputs.

## The PAL Blocks

Each PAL block in the MACH120 (Figure 1) contains a 48-product-term logic array, a logic allocator, 12 macrocells and 12 I/O cells. The switch matrix feeds each PAL block with 26 inputs. This makes the PAL block look effectively like an independent "PALCE26V12".
There are four additional output enable product terms in each PALblock. For purposes of output enable, the $12 \mathrm{I} / \mathrm{O}$ cells are divided into 2 banks of 6 macrocells. Each bank is allocated two of the output enable product terms.

An asynchronous reset product term and an asynchronous preset product term are provided for flip-flop initialization. All flip-flops within the PAL block are initialized together.

## The Switch Matrix

The MACH120 switch matrix is fed by the inputs and feedback signals from the PAL blocks. Each PAL block provides 12 internal feedback signals and 12 I/O feedback signals. The switch matrix distributes these signals back to the PAL blocks in an efficient manner that also provides for high performance. The design software automatically configures the switch matrix when fitting a design into the device.

## The Product-Term Array

The MACH120 product-term array consists of 48 product terms for logic use, and 6 special-purpose product terms. Four of the special-purpose product terms provide programmable output enable, one provides asynchronous reset, and one provides asynchronous preset. Two of the output enable product terms are used for the first six I/O cells; the other two control the last six macrocells.

## The Logic Allocator

The logic allocator in the MACH120 takes the 48 logic product terms and allocates them to the 12 macrocells as needed. Each macrocell can be driven by up to 12 product terms. The design software automatically configures the logic allocator when fitting the design into the device.
Table 1 illustrates which product term clusters are available to each macrocell within a PAL block. Refer to Figure 1 for cluster and macrocell numbers.

Table 1. Logic Allocation

| Output Macrocell | Available <br> Clusters | Output Macrocell | Available <br> Clusters |
| :---: | :---: | :---: | :---: |
| $\mathrm{M}_{0}$ | $\mathrm{C}_{0}, \mathrm{C}_{1}$ | $\mathrm{M}_{6}$ | $\mathrm{C}_{5}, \mathrm{C}_{6}, \mathrm{C}_{7}$ |
| $\mathrm{M}_{1}$ | $\mathrm{C}_{0}, \mathrm{C}_{1}, \mathrm{C}_{2}$ | $\mathrm{M}_{7}$ | $\mathrm{C}_{6}, \mathrm{C}_{7}, \mathrm{C}_{8}$ |
| $\mathrm{M}_{2}$ | $\mathrm{C}_{1}, \mathrm{C}_{2}, \mathrm{C}_{3}$ | $\mathrm{M}_{8}$ | $\mathrm{C}_{7}, \mathrm{C}_{8}, \mathrm{C}_{9}$ |
| $\mathrm{M}_{3}$ | $\mathrm{C}_{2}, \mathrm{C}_{3}, \mathrm{C}_{4}$ | $\mathrm{M}_{9}$ | $\mathrm{C}_{8}, \mathrm{C}_{9}, \mathrm{C}_{10}$ |
| $\mathrm{M}_{4}$ | $\mathrm{C}_{3}, \mathrm{C}_{4}, \mathrm{C}_{5}$ | $\mathrm{M}_{10}$ | $\mathrm{C}_{9}, \mathrm{C}_{10}, \mathrm{C}_{11}$ |
| $\mathrm{M}_{5}$ | $\mathrm{C}_{4}, \mathrm{C}_{5}, \mathrm{C}_{6}$ | $\mathrm{M}_{11}$ | $\mathrm{C}_{10}, \mathrm{C}_{11}$ |

## The M acrocell

The MACH120 macrocells can be configured as either registered or combinatorial, with programmable polarity. The macrocell provides internal feedback whether configured as registered or combinatorial. The flip-flops can be configured as D-type or T-type, allowing for product-term optimization.

The flip-flops can individually select one of four global clock pins, which are also available as logic inputs. The registers are clocked on the LOW-to-HIGH transition of the clock signal. The flip-flops can also be asynchronously initialized with the common asynchronous reset and preset product terms.

## The I/O Cell

The I/O cell in the MACH120 consists of a three-state output buffer. The three-state buffer can be configured in one of three ways: always enabled, always disabled, or controlled by a product term. If product term control is chosen, one of two product terms may be used to provide the control. The two product terms that are available are common to six I/O cells. Within each PAL block, two product terms are available for selection by the first six three-state outputs; two other product terms are available for selection by the last six three-state outputs.
These choices make it possible to use the macrocell as an output, an input, a bidirectional pin, or a three-state output for use in driving a bus.

## SpeedLocking for Guaranteed Fixed Timing

The unique MACH 1 architecture is designed for high performance-a metric that is met in both raw speed, but even more importantly, guaranteed fixed speed. Using the design of the central switch matrix, the MACH 120 product offers the SpeedLocking feature, which allows a stable fixed pin-to-pin delay, independent of logic paths, routing resources and design refits for up to 16 product terms per output. Other non-Vantis CPLDs incur serious timing delays as product terms expand beyond their typical 4 or 5 product term limits. Speed and SpeedLocking combine for continuous, high performance required in today's demanding designs


Figure 1. MACH120 PAL Block
ABSOLUTE MAXIMUM RATINGS
Storage Temperature $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$Ambient TemperatureWith Power Applied . . . . . . . . . . . . . .-55º C to $+125^{\circ} \mathrm{C}$
Device Junction Temperature

$\qquad$ ..... $+150^{\circ} \mathrm{C}$
Supply Voltage with
Respect to Ground ..... -0.5 V to +7.0 V
DC Input Voltage ..... -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$
DC Output or I/O
Pin Voltage ..... -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$
Static Discharge Voltage ..... 2001 V
Latchup Current
( $\mathrm{T}_{\mathrm{A}}=0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$ ) ..... 200 mA
Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability. Programming conditions may differ.

## OPERATING RANGES

## Commercial (C) Devices

Ambient Temperature $\left(\mathrm{T}_{\mathrm{A}}\right)$ Operating in Free Air. . . . . . . . . . . . . . . $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$
Supply Voltage ( $\mathrm{V}_{\mathrm{CC}}$ ) with Respect to Ground . . . . . . . . . +4.75 V to +5.25 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges

| Parameter Symbol | Parameter Description | Test Conditions | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\begin{aligned} & \mathrm{I}_{\mathrm{OH}}=-3.2 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}}=\operatorname{Min} \\ & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \end{aligned}$ | 2.4 |  |  | V |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage | $\begin{aligned} & \mathrm{I}_{\mathrm{OL}}=16 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Min} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \end{aligned}$ |  |  | 0.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1) | 2.0 |  |  | V |
| $\mathrm{V}_{\mathrm{IL}}$ | Input LOW Voltage | Guaranteed Input Logical LOW Voltage for all Inputs (Note 1) |  |  | 0.8 | V |
| $\mathrm{I}_{\mathrm{IH}}$ | Input HIGH Current | $\mathrm{V}_{\text {IN }}=5.25 \mathrm{~V}, \mathrm{~V}_{\text {CC }}=$ Max (Note 2) |  |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Input LOW Current | $\mathrm{V}_{\mathrm{IN}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max}$ (Note 2) |  |  | -10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {OZH }}$ | Off-State Output Leakage Current HIGH | $\begin{aligned} & \mathrm{V}_{\text {OUT }}=5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}}(\text { Note } 2) \end{aligned}$ |  |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {OLL }}$ | Off-State Output Leakage Current LOW | $\begin{aligned} & \mathrm{V}_{\mathrm{OUT}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \text { (Note 2) } \end{aligned}$ |  |  | -10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {SC }}$ | Output Short-Circuit Current | $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}, \mathrm{~V}_{\text {CC }}=$ Max (Note 3) | -30 |  | -130 | mA |
| $\mathrm{I}_{\text {CC }}$ | Supply Current (Typical) | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{f}=25 \mathrm{MHz} \\ & \text { (Note 4) } \end{aligned}$ |  | 85 |  | mA |

## Notes:

1. These are absolute values with respect to device ground and all overshoots due to system and/or tester noise are included.
2. $\mathrm{I} / \mathrm{O}$ pin leakage is the worst case of $\mathrm{I}_{\mathrm{IL}}$ and $\mathrm{I}_{\mathrm{OZL}}$ (or $\mathrm{I}_{\mathrm{IH}}$ and $\mathrm{I}_{\mathrm{OZH}}$ ).
3. Not more than one output should be shorted at a time. Duration of the short-circuit should not exceed one second. $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}$ has been chosen to avoid test problems caused by tester ground degradation.
4. Measured with a 12-bit up/down counter pattern. This pattern is programmed in each PALblock and capable of being loaded, enabled, and reset.

CAPACITANCE (Note 1)

| Parameter <br> Symbol | Parameter Description | Test Conditions |  | Typ | Unit |
| :---: | :--- | :--- | :--- | :---: | :---: |
| $\mathrm{C}_{\mathrm{IN}}$ | Input Capacitance | $\mathrm{V}_{\text {IN }}=2.0 \mathrm{~V}$ | $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ <br> $\mathrm{f}=1 \mathrm{MHz}$ | 6 | pF |
| $\mathrm{C}_{\text {OUT }}$ | Output Capacitance | $\mathrm{V}_{\text {OUT }}=2.0 \mathrm{~V}$ |  | 8 | pF |

## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

| Parameter Symbol | Parameter Description |  |  | -12 |  | -15 |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | Min | Max | Min | Max |  |
| $t_{\text {PD }}$ | Input, I/O, or Feedback to Combinatorial Output |  |  |  | 12 |  | 15 | ns |
| $\mathrm{t}_{\text {s }}$ | Setup Time from Input, I/O, or Feedback to Clock |  | D-type | 7 |  | 10 |  | ns |
|  |  |  | T-type | 8 |  | 11 |  | ns |
| $\mathrm{t}_{\mathrm{H}}$ | Hold Time |  |  | 0 |  | 0 |  | ns |
| $\mathrm{t}_{\mathrm{CO}}$ | Clock to Output |  |  |  | 8 |  | 10 | ns |
| $t_{\text {WL }}$ | CLock Width |  | LOW | 6 |  | 6 |  | ns |
| $\mathrm{t}_{\mathrm{WH}}$ |  |  | HIGH | 6 |  | 6 |  | ns |
| $\mathrm{f}_{\text {MAX }}$ | Maximum <br> Frequency <br> (Note 1) | External <br> Feedback | D-type | 66.7 |  | 50 |  | MHz |
|  |  |  | T-type | 62.5 |  | 47.6 |  | MHz |
|  |  | Internal <br> Feedback ( $\mathrm{f}_{\mathrm{CNT}}$ ) | D-type | 76.9 |  | 66.6 |  | MHz |
|  |  |  | T-type | 71.4 |  | 55.5 |  | MHz |
|  |  | No Feedback |  | 83.3 |  | 83.3 |  | MHz |
| $\mathrm{t}_{\text {AR }}$ | Asynchronous Reset to Registered Output |  |  |  | 16 |  | 20 | ns |
| $\mathrm{t}_{\text {ARW }}$ | Asynchronous Reset Width (Note 1) |  |  | 12 |  | 15 |  | ns |
| $\mathrm{t}_{\text {ARR }}$ | Asynchronous Reset Recovery Time (Note 1) |  |  | 8 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{AP}}$ | Asynchronous Preset to Registered Output |  |  |  | 16 |  | 20 | ns |
| $\mathrm{t}_{\text {APW }}$ | Asynchronous Preset Width (Note 1) |  |  | 12 |  | 15 |  | ns |
| $\mathrm{t}_{\text {APR }}$ | Asynchronous Preset Recovery Time (Note 1) |  |  | 8 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{EA}}$ | Input, I/O, or Feedback to Output Enable |  |  |  | 12 |  | 15 | ns |
| $\mathrm{t}_{\mathrm{ER}}$ | Input, I/O, or Feedback to Output Disable |  |  |  | 12 |  | 15 | ns |

## Notes:

1. These parameters are not $100 \%$ tested, but are evaluated at initial characterization and at any time the design is modified where frequency may be affected.
2. See Switching Test Circuit, for test conditions.
ABSOLUTE MAXIMUM RATINGS
Storage Temperature $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$Ambient TemperatureWith Power Applied . . . . . . . . . . . . . $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
Device Junction Temperature

$\qquad$ ..... $+150^{\circ} \mathrm{C}$
Supply Voltage withRespect to Ground
$\qquad$DC Input Voltage . . . . . . . . . . . . -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$DC Output or I/O
Pin Voltage ..... -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$
Static Discharge Voltage ..... 2001 V
Latchup Current
$\left(\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}\right.$ to $+85^{\circ} \mathrm{C}$ ) .....  . . . . . . . . . . . . . . . . . 200 mA
Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability. Programming conditions may differ.

## INDUSTRIAL OPERATING RANGES

## Industrial (I) Devices

Ambient Temperature $\left(\mathrm{T}_{\mathrm{A}}\right)$ Operating in Free Air. . . . . . . . . . . . . . $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
Supply Voltage ( $\mathrm{V}_{\mathrm{CC}}$ )
with Respect to Ground . . . . . . . . . . . +4.5 V to +5.5 V
Operating ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over INDUSTRIAL operating ranges

| Parameter Symbol | Parameter Description | Test Conditions | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | $\begin{aligned} & \mathrm{I}_{\mathrm{OH}}=-3.2 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Min} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \end{aligned}$ | 2.4 |  |  | V |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage | $\begin{aligned} & \mathrm{I}_{\mathrm{OL}}=16 \mathrm{~mA}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Min} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \end{aligned}$ |  |  | 0.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1) | 2.0 |  |  | V |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage | Guaranteed Input Logical LOW Voltage for all Inputs (Note 1) |  |  | 0.8 | V |
| $\mathrm{I}_{\mathrm{IH}}$ | Input HIGH Current | $\mathrm{V}_{\mathrm{IN}}=5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max}$ (Note 2) |  |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Input LOW Current | $\mathrm{V}_{\mathrm{IN}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max}$ (Note 2) |  |  | -10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {OZH }}$ | Off-State Output Leakage Current HIGH | $\begin{aligned} & \mathrm{V}_{\mathrm{OUT}}=5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Max} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}}(\text { Note } 2) \end{aligned}$ |  |  | 10 | $\mu \mathrm{A}$ |
| IozL | Off-State Output Leakage Current LOW | $\begin{aligned} & \mathrm{V}_{\text {OUT }}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{CC}}=\text { Max } \\ & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}}(\text { Note } 2) \end{aligned}$ |  |  | -10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {SC }}$ | Output Short-Circuit Current | $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}, \mathrm{~V}_{\text {CC }}=\mathrm{Max}$ (Note 3) | -30 |  | -130 | mA |
| $\mathrm{I}_{\mathrm{CC}}$ | Supply Current (Typical) | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{f}=25 \mathrm{MHz}$ (Note 4) |  | 85 |  | mA |

## Notes:

1. These are absolute values with respect to device ground and all overshoots due to system and/or tester noise are included.
2. $\mathrm{I} / \mathrm{O}$ pin leakage is the worst case of $\mathrm{I}_{\mathrm{IL}}$ and $\mathrm{I}_{\mathrm{OZL}}$ (or $\mathrm{I}_{\mathrm{IH}}$ and $\mathrm{I}_{\mathrm{OZH}}$ ).
3. Not more than one output should be shorted at a time. Duration of the short-circuit should not exceed one second. $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}$ has been chosen to avoid test problems caused by tester ground degradation.
4. Measured with a 12-bit up/down counter pattern. This pattern is programmed in each PALblock and is capable of being loaded, enabled, and reset.

## CAPACITANCE (Note 1)

| Parameter <br> Symbol | Parameter Description | Test Conditions |  | Typ | Unit |
| :---: | :--- | :--- | :--- | :---: | :---: |
| $\mathrm{C}_{\text {IN }}$ | Input Capacitance | $\mathrm{V}_{\mathrm{IN}}=2.0 \mathrm{~V}$ | $\mathrm{~V}_{\mathrm{CC}}=5.0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 6 | pF |
| $\mathrm{C}_{\mathrm{OUT}}$ | Output Capacitance | $\mathrm{V}_{\mathrm{OUT}}=2.0 \mathrm{~V}$ | $\mathrm{f}=1 \mathrm{MHz}$ | 8 | pF |

## SWITCHING CHARACTERISTICS over INDUSTRIAL operating ranges (Note 2)

| Parameter Symbol | Parameter Description |  |  |  |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  | Min | Max |  |
| $\mathrm{t}_{\text {PD }}$ | Input, I/O, or Feedback to Combinatorial Output (Note 3) |  |  |  |  | 18 | ns |
| $t_{s}$ | Setup Time from Input, I/O, or Feedback |  |  | D-type | 12 |  | ns |
|  |  |  |  | T-type | 13.5 |  | ns |
| $\mathrm{t}_{\mathrm{H}}$ | Hold Time |  |  |  | 0 |  | ns |
| $\mathrm{t}_{\mathrm{CO}}$ | Clock to Output (Note 3) |  |  |  |  | 12 | ns |
| $\mathrm{t}_{\mathrm{WL}}$ | Clock Width |  |  | LOW | 7.5 |  | ns |
| $\mathrm{t}_{\mathrm{WH}}$ |  |  |  | HIGH | 7.5 |  | ns |
| $\mathrm{f}_{\text {MAX }}$ | Maximum <br> Frequency (Note <br> 1) | External Feedback | $1 /\left(\mathrm{t}_{\mathrm{S}}+\mathrm{t}_{\mathrm{CO}}\right)$ | D-type | 40 |  | MHz |
|  |  |  |  | T-type | 38 |  | MHz |
|  |  | Internal Feedback ( $\mathrm{f}_{\mathrm{CNT}}$ ) |  | D-type | 53 |  | MHz |
|  |  |  |  | T-type | 44 |  | MHz |
|  |  | No Feedback | $1 /\left(\mathrm{t}_{\mathrm{WL}}+\mathrm{t}_{\mathrm{WH}}\right)$ |  | 66.5 |  | MHz |
| $t_{\text {AR }}$ | Asynchronous Reset to Registered Output |  |  |  |  | 24 | ns |
| $\mathrm{t}_{\text {ARW }}$ | Asynchronous Reset Width (Note 1) |  |  |  | 18 |  | ns |
| $\mathrm{t}_{\text {ARR }}$ | Asynchronous Reset Recovery Time (Note 1) |  |  |  | 12 |  | ns |
| $\mathrm{t}_{\text {AP }}$ | Asynchronous Preset to Registered Output |  |  |  |  | 24 | ns |
| $\mathrm{t}_{\text {APW }}$ | Asynchronous Preset Width (Note 1) |  |  |  | 18 |  | ns |
| $\mathrm{t}_{\text {APR }}$ | Asynchronous Preset Recovery Time (Note 1) |  |  |  | 12 |  | ns |
| $\mathrm{t}_{\mathrm{EA}}$ | Input, I/O, or Feedback to Output Enable (Note 3) |  |  |  |  | 18 | ns |
| $\mathrm{t}_{\mathrm{ER}}$ | Input, I/O, or Feedback to Output Disable (Note 3) |  |  |  |  | 18 | ns |

## Notes:

1. These parameters are not $100 \%$ tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.
2. See Switching Test Circuit, for test conditions.
3. Parameters measured with 24 outputs switching.

TYPICAL CURRENT vs. VOLTAGE (I-V) CHARACTERISTICS
$\mathrm{V}_{\mathrm{cc}}=5.0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathbf{2 5}{ }^{\circ} \mathrm{C}$


Output, LOW


Output, HIGH


## TYPICAL IcC CHARACTERISTICS

$\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$


14129J-7

The selected "typical" pattern is a 12-bit up/down counter. This pattern is programmed in each PAL block and is capable of being loaded, enabled, and reset.
Maximum frequency shown uses internal feedback and a D-type register.

## TYPICAL THERM AL CHARACTERISTICS

Measured at $25^{\circ} \mathrm{C}$ ambient. These parameters are not tested.

| Parameter Symbol | Parameter Description |  | Typ | Unit |
| :---: | :---: | :---: | :---: | :---: |
|  |  |  | PLCC |  |
| $\theta_{\mathrm{jc}}$ | Thermal impedance, junction to case |  | 13 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\theta_{\mathrm{ja}}$ | Thermal impedance, junction to ambient |  | 37 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\theta_{\text {jma }}$ | Thermal impedance, junction to ambient with air flow | 200 lfpm air | 33 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | 400 lfpm air | 30 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | 600 lfpm air | 28 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | 800 lfpm air | 25 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

## Plastic 日jc Considerations

The data listed for plastic $\theta j c$ are for reference only and are not recommended for use in calculating junction temperatures. The heat-flow paths in plastic-encapsulated devices are complex, making the $\theta j c$ measurement relative to a specific location on the package surface. Tests indicate this measurement reference point is directly below the die-attach area on the bottom center of the package. Furthermore, $\theta j$ cests on packages are performed in a constant-temperature bath, keeping the package surface at a constant temperature. Therefore, the measurements can only be used in a similar environment. The thermal measurements are taken with components on a six-layer printed circuit board.

## SWITCHING WAVEFORMS



## Notes:

1. $\mathrm{V}_{\mathrm{T}}=1.5 \mathrm{~V}$.
2. Input pulse amplitude 0 V to 3.0 V .
3. Input rise and fall times $2 \mathrm{~ns}-4 \mathrm{~ns}$ typical.

## SWITCHING WAVEFORMS



14129J-11
Asynchronous Reset


14129J-12
Asynchronous Preset


Output Disable/Enable

## Notes:

1. $\mathrm{V}_{\mathrm{T}}=1.5 \mathrm{~V}$.
2. Input pulse amplitude 0 V to 3.0 V .
3. Input rise and fall times $2 \mathrm{~ns}-4 \mathrm{~ns}$ typical.

## KEY TO SWITCHING WAVEFORMS

$\left.\begin{array}{lll}\text { WAVEFORM } & \text { INPUTS } & \text { OUTPUTS } \\ & \begin{array}{l}\text { Must be } \\ \text { Steady }\end{array} & \begin{array}{l}\text { Will be } \\ \text { Steady }\end{array} \\ \text { May } \\ \text { Change } \\ \text { from H to L }\end{array} \quad \begin{array}{l}\text { Will be } \\ \text { Changing } \\ \text { from H to L }\end{array}\right\}$

KS000010-PAL

## SWITCHING TEST CIRCUIT



| Specification | $\mathrm{S}_{1}$ | $\mathrm{C}_{\mathrm{L}}$ | Commercial |  | Measured Output Value |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | $\mathrm{R}_{1}$ | $\mathrm{R}_{2}$ |  |
| $\mathrm{t}_{\mathrm{PD}}, \mathrm{t}_{\mathrm{CO}}$ | Closed | 35 pF | $300 \Omega$ | $390 \Omega$ |  |
| $\mathrm{t}_{\mathrm{EA}}$ | $\begin{aligned} & \mathrm{Z} \rightarrow \mathrm{H}: \text { Open } \\ & \mathrm{Z} \rightarrow \mathrm{~L}: \text { Closed } \end{aligned}$ |  |  |  | 1.5 V |
| $\mathrm{t}_{\text {ER }}$ | $\begin{aligned} & \mathrm{H} \rightarrow \mathrm{Z}: \text { Open } \\ & \mathrm{L} \rightarrow \mathrm{Z}: \text { Closed } \end{aligned}$ | 5 pF |  |  | $\begin{aligned} \mathrm{H} & \rightarrow \mathrm{Z}: \mathrm{V}_{\mathrm{OH}}-0.5 \mathrm{~V} \\ \mathrm{~L} & \rightarrow \mathrm{Z}: \mathrm{V}_{\mathrm{OL}}+0.5 \mathrm{~V} \end{aligned}$ |

*Switching several outputs simultaneously should be avoided for accurate measurement.

## $F_{\text {max }}$ PARAMETERS

The parameter $\mathrm{f}_{\text {MAX }}$ is the maximum clock rate at which the device is guaranteed to operate. Because the flexibility inherent in programmable logic devices offers a choice of clocked flip-flop designs, $\mathrm{f}_{\text {MAX }}$ is specified for three types of synchronous designs.
The first type of design is a state machine with feedback signals sent off-chip. This external feedback could go back to the device inputs, or to a second device in a multi-chip state machine. The slowest path defining the period is the sum of the clock-to-output time and the input setup time for the external signals ( $\mathrm{t}_{\mathrm{S}}+\mathrm{t}_{\mathrm{CO}}$ ). The reciprocal, $\mathrm{f}_{\mathrm{MAX}}$, is the maximum frequency with external feedback or in conjunction with an equivalent speed device. This $\mathrm{f}_{\mathrm{MAX}}$ is designated " $\mathrm{f}_{\mathrm{MAX}}$ external."
The second type of design is a single-chip state machine with internal feedback only. In this case, flip-flop inputs are defined by the device inputs and flip-flop outputs. Under these conditions, the period is limited by the internal delay from the flip-flop outputs through the internal feedback and logic to the flip-flop inputs. This $\mathrm{f}_{\text {MAX }}$ is designated " $\mathrm{f}_{\text {MAX }}$ internal". A simple internal counter is a good example of this type of design; therefore, this parameter is sometimes called "f $\mathrm{f}_{\mathrm{CNT}}$."
The third type of design is a simple data path application. In this case, input data is presented to the flip-flop and clocked through; no feedback is employed. Under these conditions, the period is limited by the sum of the data setup time and the data hold time $\left(\mathrm{t}_{\mathrm{S}}+\mathrm{t}_{\mathrm{H}}\right)$. However, a lower limit for the period of each $f_{M A X}$ type is the minimum clock period ( $t_{W H}+t_{W L}$ ). Usually, this minimum clock period determines the period for the third $\mathrm{f}_{\mathrm{MAX}}$, designated " $\mathrm{f}_{\mathrm{MAX}}$ no feedback."
For devices with input registers, one additional $f_{\text {MAX }}$ parameter is specified: $f_{\text {MAXIR. }}$. Because this involves no feedback, it is calculated the same way as $f_{M A X}$ no feedback. The minimum period will be limited either by the sum of the setup and hold times ( $\mathrm{t}_{\text {SIR }}+\mathrm{t}_{\mathrm{HIR}}$ ) or the sum of the clock widths ( $\mathrm{t}_{\text {WICL }}+\mathrm{t}_{\text {WICH }}$ ). The clock widths are normally the limiting parameters, so that $\mathrm{f}_{\text {MAXIR }}$ is specified as $1 /\left(t_{\text {WICL }}+t_{\text {WICH }}\right)$. Note that if both input and output registers are use in the same path, the overall frequency will be limited by $\mathrm{t}_{\text {ICS }}$.
All frequencies except $f_{\text {MAX }}$ internal are calculated from other measured AC parameters. $f_{\text {MAX }}$ internal is measured directly.


## ENDURANCE CHARACTERISTICS

The MACH families are manufactured using Vantis’ advanced Electrically Erasable process. This technology uses an EE cell to replace the fuse link used in bipolar parts. As a result, the device can be erased and reprogrammed, a feature which allows $100 \%$ testing at the factory.

Endurance Characteristics

| Parameter <br> Symbol | Parameter Description |  | Units | Test Conditions |
| :---: | :--- | :---: | :---: | :--- |
| $\mathrm{t}_{\mathrm{DR}}$ | Min Pattern Data Retention Time | 10 | Years | Max Storage Temperature |
|  |  | 20 | Years | Max Operating Temperature |
| N | Max Reprogramming Cycles | 100 | Cycles | Normal Programming Conditions |

## INPUT/OUTPUT EQUIVALENT SCHEMATICS



## POWER-UP RESET

The MACH devices have been designed with the capability to reset during system power-up. Following power-up, all flip-flops will be reset to LOW. The output state will depend on the logic polarity. This feature provides extra flexibility to the designer and is especially valuable in simplifying state machine initialization. A timing diagram and parameter table are shown below. Due to the synchronous operation of the power-up reset and the wide range of ways $V_{C C}$ can rise to its steady state, two conditions are required to insure a valid power-up reset. These conditions are:

1. The $\mathrm{V}_{\mathrm{CC}}$ rise must be monotonic.
2. Following reset, the clock input must not be driven from LOW to HIGH until all applicable input and feedback setup times are met.

| Parameter <br> Symbol | Parameter Descriptions | Max | Unit |
| :---: | :--- | :---: | :---: |
| $\mathrm{t}_{\mathrm{PR}}$ | Power-Up Reset Time | 10 | $\mu \mathrm{~s}$ |
| $\mathrm{t}_{\mathrm{S}}$ | Input or Feedback Setup Time | See <br> Switching <br> Characteristics |  |
| $\mathrm{t}_{\mathrm{WL}}$ | Clock Width LOW |  |  |



## Power-Up Reset Waveform

